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SU9000 / Regulus 8230 / Regulus 8100 / SU7000 / SU5000

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Model	Ultra-high Resolution Scanning Electron Microscope SU9000 	Ultra-high Resolution Scanning Electron Microscope Regulus 8230 	Ultra-high Resolution Scanning Electron Microscope Regulus 8100 	Ultra-High-Resolution Schottky Scanning Electron Microscope SU7000 	Schottky Field Emission Scanning Electron Microscope SU5000 
Magnification	×80 - ×3,000,000 (on photo) ×220 - ×8,000,000 (on display)	×20 - ×2,000,000	×20 - ×1,000,000	×20 - ×2,000,000	×10 - ×600,000 (on photo) ×18 - ×1,000,000 (on display)
Resolution	0.34 nm at 30 kV (STEM)* 0.4 nm at 30 kV (SE) 1.2 nm at 1 kV (SE) 0.8 nm at 1 kV (SE/Deceleration mode)*	0.6 nm at 15 kV (SE) 0.7 nm at 1 kV (SE)	0.7 nm at 15 kV (SE) 0.8 nm at 1 kV (SE)	0.8 nm at 15 kV (SE) 0.9 nm at 1 kV (SE)	1.2 nm at 30 kV (SE) 3.0 nm at 1 kV (SE) 2.0 nm at 1 kV (SE with deceleration)* 1.6 nm at 1 kV (SE with EX deceleration)* 3.0 nm at 15 kV (BSE, variable pressure mode)*
Electron source	Cold cathode field emitter			ZrO / W Schottky emitter	
Accelerating voltage	0.5 - 30 kV			0.1 - 30 kV	0.5 - 30 kV
Landing voltage	0.1 - 2 kV*	0.01 - 20 kV	0.1 - 20 kV	0.01 - 7 kV*	0.1 - 20 kV*
Variable pressure				5 - 300 Pa*	10 - 300 Pa*
Sample stage traverse	Side entry goniometer stage X : ±4.0 mm Y : ±2.0 mm Z : ±0.3 mm T : ±40°	5-axis motorized stage X : 0 - 110 mm Y : 0 - 110 mm Z : 1.5 - 40 mm T : -5 - 70° R : 360°	3 or 5* -axis motorized stage X : 0 - 50 mm Y : 0 - 50 mm Z : 1.5 - 30 mm T : -5 - 70° R : 360°	5-axis motorized stage X : 0 - 135 mm Y : 0 - 100 mm Z : 1.5 - 40 mm T : -5 - 70° R : 360°	5-axis motorized stage X : 0 - 100 mm Y : 0 - 50 mm Z : 3 - 65 mm T : -20 - 90° R : 360°
Maximum sample size	Bulk : 5.0 mm x 9.5 mm x 3.5 mmH Cross-section : 2.0 mm x 6.0 mm x 5.0 mmH Double tilt cross-section specimen holder (L) : 0.8 mm x 8.5 mm x 3.5 mmH	200 mm (in diameter)	100 mm (in diameter)	200 mm (in diameter)	
Maximum sample thickness	27 mm		17 mm	80 mm	
Signal detector	Secondary electron detector Top detector* BF/DF Duo-STEM detector* Energy dispersive X-ray detector*	Upper detector (with SE/BSE signal mixing function) Lower detector Top detector BSE detector* TE detector*	Upper detector (with SE/BSE signal mixing function) Lower detector BSE detector* TE detector*	Upper detector (UD) Middle detector (MD) Lower detector (LD) Semiconductor type BSE detector (PD-BSED)* Ultra Variable-Pressure Detector (UVD)* TE detector*	SE detector Top detector* Semiconductor type BSE detector (PD-BSED)* Ultra Variable pressure-Detector (UVD)* TE detector*
Analysis system	Energy Dispersive X-ray Spectrometer (EDS)* Electron Energy Loss Spectrometer (EELS)* Electron Diffraction*	Energy Dispersive X-ray Spectrometer (EDS)* Electron Backscatter Diffraction (EBSD)*	Energy Dispersive X-ray Spectrometer (EDS)*	Energy Dispersive X-ray Spectrometer (EDS)* Electron Backscatter Diffraction (EBSD)* Wavelength Dispersive X-ray Spectrometer (WDS)*	